US Patent Application Serial No. 10/797,993 Amendment Dated 10/14/2005 Reply to Office Action Dated 7/14/2005

Amendment to the Specification

Please replace the Abstract with the following Abstract:

--A calibration technique is presented for calibrating non-reference indirect measurement systems with respect to a reference indirect measurement system. A reference map function fitting procedure fits a reference map function based on known values of a parameter of interest associated with reference calibration samples and corresponding reference values associated with the reference calibration samples. A correction function fitting procedure fits a correction function based on reference values for calibration samples measured on or simulated for the reference indirect measurement system and corresponding values measured on the non-reference indirect measurement system. During normal use, the non-reference indirect measurement system obtains measurements, corrects the measurements using the correction function, and estimates the parameter of interest of the object of interest using the reference map function based on the corrected measurements.--.